26th IEEE European Test Symposium
Virtual Interactive Event
May 24 – 28, 2021, Belgium
www.ets2021.eu

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CALL FOR PAPERS – Regular Papers

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, hot topics, and new trends, industrial case-studies and applications, in the area of electronic-based circuits and system testing, reliability, safety, security and validation. The 2021 edition of ETS will be a virtual one. The organizing team will strive to keep the spirit of ETS alive, by organizing an event with live sessions and many opportunities for networking and peer interaction. ETS'21 is organized jointly by imec and KU Leuven, which co-sponsor the event together with the IEEE Council on Electronic Design Automation (CEDA).

The program includes keynotes, scientific paper presentations, panels, tutorials, workshops and highlights/demos from industry.

ETS'21 provides the opportunity of submitting Regular technical papers presenting novel and complete research work. Papers submitted under this category should be of maximum 6 pages in the IEEE 2-column format.

You are invited to participate and submit your contributions to ETS'21. The areas of interest include (but are not limited to) the following topics:

- Analog, Mixed-Signal and RF Test
- Approximate Circuit Testing
- ATE Hardware and Software
- Automatic Test Generation
- Automotive and Avionics Test
- Board Test and Diagnosis
- Built-In Self-Test
- Current-Based Test
- Defect-Based Test
- Delay and Performance Test
- Dependability and Functional Safety
- Design for Test
- DfX (Design for Manufacturing, Reliability, Yield, etc.)
- Diagnosis and Silicon Debug
- Economics of Test

- Failure Analysis
- Fault Modeling and Simulation
- Fault Tolerance
- Hardware Security
- Hardware Trust
- High-Speed I/0 Test
- Low-Power Test
- Machine Learning and AI for Test
- Memory Test and Repair
- Microsystems / MEMS / Sensors Test
- On-Line Test
- Power- / Thermal-Aware Test
- Processor Test (Multi-Core, GPU, CPU, Neuromorphic, etc.)
- Security Issues in Test

- Self-X (Awareness, Repair, Test, etc.)
- Signal Integrity Test
- SoC and NoC Test
- Stacked or 3D ICs Test
- Standards in Test
- Test of Reconfigurable Systems (FPGA, CPLD, etc.)
- Test, Reliability and Security of Emerging Technologies
- Test, Reliability and Security of Emerging Computing (Neuromorphic, In-Memory, Reversible and Quantum Circuits, etc.)
- Trojan Detection
- Verification and Validation
- Yield Analysis and Enhancement

Publications: ETS'21 will produce Formal Proceedings of scientific papers with ISBN number that will be included in the IEEE Xplore Digital Library. Extended versions of selected papers will be invited for submission in an IEEE Journal Special Issue dedicated to ETS'21.

Key Dates for Submissions:

Scientific Papers: Title and abstract	December 10th, 2020
Full Paper	December 17th, 2020
Notification of acceptance:	February 12th, 2021
Camera-ready manuscript:	March 15th, 2021

In preparations for ETS'21, the organizing team will work on finding the best conference format to ensure lively interactions and networking opportunities. Updated information will always be available on the ETS'21 website.

Further Information:

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